## SN74ALS29863 9-BIT TRANSCEIVER WITH 3-STATE OUTPUTS

SDAS096C - JANUARY 1986 - REVISED JANUARY 1995

- Functionally Equivalent to AMD's AM29863
- Power-Up High-Impedance State
- **Package Options Include Plastic** Small-Outline (DW) Packages and Standard Plastic (NT) 300-mil DIPs

#### description

This 9-bit transceiver is designed for asynchronous two-way communication between data buses. The control-function implementation allows for maximum flexibility in timing.

This device allows data transmission from the A bus to the B bus or from the B bus to the A bus, depending on the logic levels at the output-enable (OEAB1, OEAB2, OEBA1, and OEBA2) inputs.

The SN74ALS29863 is characterized for operation from 0°C to 70°C.

	OR NT I (TOP V		AGE
OEBA1	1	24	V <sub>CC</sub>
A1	2	23	B1
A2	3	22	B2
A3	4	21	B3
A4	5	20	B4
A5	6	19	B5
A6	7	18	B6
A7	8	17	B7
A8	9	16	B8
A9	10	15	B9
OEBA2	11	14	OEAB2
GND	12	13	OEAB1

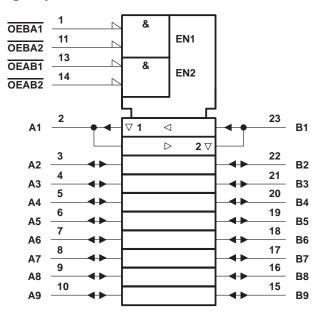
INPUTS OPERATION		FUNCTION TABLE							
	INPUTS								
DEAB2 OEBA1 OEBA2	OEBA2	OEBA1	OEAB2	OEAB1					
L L L Latch A and B	L	L	L	L					
L H X A to B	Х	Н	L	L					
L X H	Н	Х	L	L					
X L L Bto A	L	L	Х	Н					
H L L BIOA	L	L	Н	Х					
х н х	Х	Н	Х	Н					
X X H Isolation	Н	Х	Х	н					
H X H	Н	Х	Н	Х					
н н х	Х	Н	Н	Х					

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

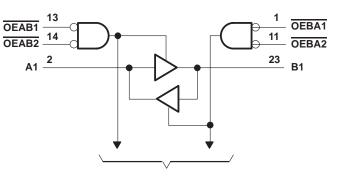


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### logic symbol<sup>†</sup>



logic diagram (positive logic)



To Eight Other Channels

<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>‡</sup>

Supply voltage, V <sub>CC</sub>	V
Input voltage, V <sub>I</sub> (all inputs and I/O ports) 5.5 V	V
Operating free-air temperature range, T <sub>A</sub>	С
Storage temperature range	С

‡ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions

		MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.75	5	5.25	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			0.8	V
ЮН	High-level output current			-24	mA
IOL	Low-level output current			48	mA
TA	Operating free-air temperature	0		70	°C



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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

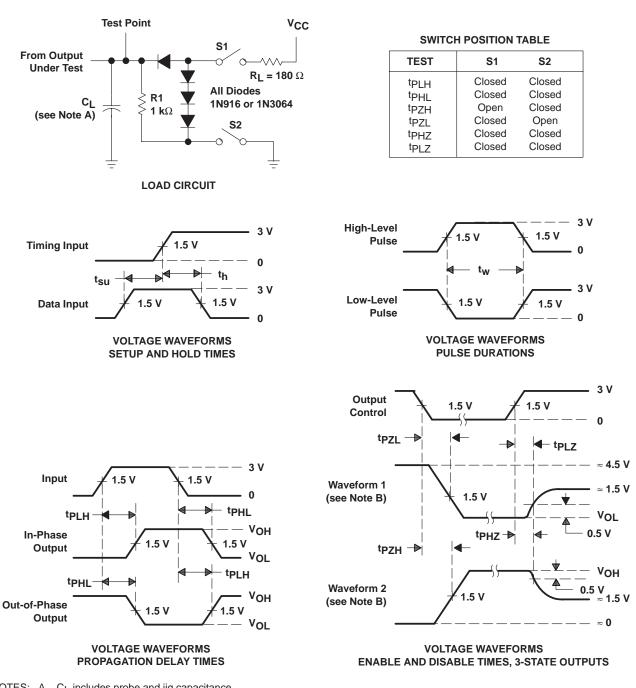
PARAMETER		TEST CON	TEST CONDITIONS		TYP <sup>†</sup>	MAX	UNIT
VIK		V <sub>CC</sub> = 4.75 V,	I <sub>I</sub> = -18 mA			-1.2	V
Vou		Voo - 4.75 V	I <sub>OH</sub> = -15 mA	2.4			V
∨он		$V_{CC} = 4.75 \text{ V}$ $I_{OH} = -24 \text{ mA}$		2			v
VOL		V <sub>CC</sub> = 4.75 V,	I <sub>OL</sub> = 48 mA		0.35	0.5	V
Ц		V <sub>CC</sub> = 5.25 V,	V <sub>I</sub> = 5.5 V			0.1	mA
1	Control inputs		V <sub>I</sub> = 2.7 V			20	۵
ľн	A or B ports <sup>‡</sup>	V <sub>CC</sub> = 5.25 V,				20	μA
۱	Control inputs				-0.1	mA	
	A or B ports <sup>‡</sup>	V <sub>CC</sub> = 5.25 V,	V <sub>I</sub> = 0.4 V			-0.1	ША
los§		V <sub>CC</sub> = 5.25 V,	VO = 0	-75		-250	mA
ICC		V <sub>CC</sub> = 5.25 V			40	65	mA

<sup>†</sup> All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C. <sup>‡</sup> For I/O ports, the parameters I<sub>IH</sub> and I<sub>IL</sub> include the off-state output current. § Not more than one output should be shorted at a time and duration of the short circuit should not exceed one second.

#### switching characteristics (see Figure 1)

PARAMETER	FROM	то	TEST CONDITIONS	V <sub>CC</sub> = 4.75 V to 5.25 V		UNIT	
PARAWETER	(INPUT)	(OUTPUT)	TEST CONDITIONS	MIN	MAX		
<sup>t</sup> PLH	A or B	DanA	B or A C <sub>L</sub> = 300 pF	15	15	ns	
<sup>t</sup> PHL	AUB	B or A			15	115	
<sup>t</sup> PLH	A or B		C <sub>L</sub> = 50 pF		8		
<sup>t</sup> PHL		B or A			8	ns	
<sup>t</sup> PZH	OEAB or OEBA	A as D	0 000 - 5		20		
<sup>t</sup> PZL	OEAB OF OEBA	A or B	C <sub>L</sub> = 300 pF		23	ns	
<sup>t</sup> PZH		A D	A == D = 0 = 50 = 5	15	15	ns	
<sup>t</sup> PZL	OEAB or OEBA	A or B	C <sub>L</sub> = 50 pF		15	115	
<sup>t</sup> PHZ				17			
<sup>t</sup> PLZ	OEAB or OEBA	A or B	C <sub>L</sub> = 50 pF		12	ns	
<sup>t</sup> PHZ		A or B	0. 5		9		
<sup>t</sup> PLZ	OEAD OF OEBA	AUIB	C <sub>L</sub> = 5 pF		9	ns	





#### PARAMETER MEASUREMENT INFORMATION

NOTES: A.  $C_L$  includes probe and jig capacitance.

Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Β. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control. C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>f</sub>  $\leq$  2.5 ns, t<sub>f</sub>  $\leq$  2.5 ns.

Figure 1. Load Circuit and Voltage Waveforms



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